

 \sim

 $\ddot{}$ $\ddot{}$

- 3.1.5 DCM-2, Rev. **1,** 1/18/91, Preparation and Control of Calculations and Analyses.
- * 3.1.6 Master Equipment List, LVOLT System, dated 4/2/90.

 $\ddot{}$

 \sim

New York Power

 $\mathcal{L}^{\mathcal{L}}$

 \sim

 $\ddot{}$

 Δ

 \mathcal{L}

 \mathbb{R}^2

6.0 LOOP UNCERTAINTY EQUATIONS

(SEE ATTACHMENT I)

6.1 LOOP COMPONENTS (Ref. 3.1.6)

7.0 DETERMINE CHANNEL UNCERTAINTY (CU)

Total Channel Uncertainty (CU)

The total Channel Uncertainty is calculated for the Undervoltage Relays, the Undervoltage Time Delay Relays, the Underfrequency Relays and the Underfrequency Relay Time Delay as follows. The methodology is described in Attachment I:

a) $CU = \pm \sqrt{PM^2 + PB^2 + IRE^2 + e_1^2} \pm B^*$ (Undervoltage (LOV) Relays) $=$ $\pm \sqrt{0^2 + 0^2 + 3^2}$, -3 **" *39, -3** *VAC* **" +39** *VAC " -42VAC* **b)** $CU = \pm \sqrt{PM^2 + PE^2 + IRE^2 + e_2^2 + B^*}$ (Undervoltage (LOV) Time Delay Relays) $= \pm \sqrt{0^2 + 0^2 + 0^2 + 11^2}, \pm 5\}$ **- *11%, +5%** *of Setting*

 $CU = +16%$

= -11% of Setting

 \cdot

÷.

7.4.8 Measurement and Test Equipment uncertainty (MTE₁)

The following instrument is used to test the Undervoltage relays, as shown in the block diagram (Section 5.0) and Ref. 3.4.4:

MTE₁: Digital Volt Meter (DVM)

The reference standards used for calibrating M&TE have an uncertainty (error) requirement of not more than 1/4 of the tolerance of the equipment being calibrated (Ref. 3.4.3).

Measuring and Test Equipment shall have an accuracy greater than or equal to that of the equipment being calibrated (Ref. 3.4.2).

Given the relative high accuracy of the M&TE, and the procedural guidelines stated above, it is conservative to assume that:

MTE **-** The value used as the relay Reference Accuracy (RA), including any M&TE reading error, and reference standard uncertainty.

Therefore,

 $MTE_1 - \pm 3$ VAC

7.4.9 Power Supply Effect $(PS_1) = 0$ %

The undervoltage relays are powered from the potential transformers on the 6.9kV bus. Therefore, any PS effects are included in Sec. 7.2.

7.5 Undervoltage (LOV) Time Delay Relay Uncertainty, (e₂)

 $\theta_2 = \pm \sqrt{RA_2^2 + DR_1^2 + TE_2^2 + RE_1^2 + SE_2^2 + HE_2^2 + SP_2^2 + MTE_2^2 + PS_2^2 + B_2^2}$

 $\pm \sqrt{5^2 + 6.3^2 + 5.7^2 + 0^2 + 0^2 + 5^2 + 0^2}$, +5%

e= **=t11, +5%** of setting, given the following Undervoltage (LOV) Relay time delay uncertainties:

FORM DCM 2, 4.2 (JAN. 1991)

 \sim \sim

FORM **DCM** 2, 4.2 (JAN. 1991)

 \mathcal{L}

The relays are located in a mild environment.

No temperature uncertainties are identified by the vendor for the Underfrequency relays time delay. (Ref. 3.6.2)

However, calibrations are performed at different times of the year, at various ambient temperatures. Therefore, it is conservative to assume that any temperature effect is included in Section 7.6.2.

 $7.6.4$ Radiation effect $(RE_3) = 0$

The underfrequency relays are located in a mild environment.

- 7.6.5 Seismic Effect $(SE_3) = 0$ (Assumption 2.1)
- 7.6.6 Humidity Effect $(HE_3) = 0$

The underfrequency relays are located in a mild environment.

 $7.6.7$ Static Press. Effect $(SP_3) = 0$

Pressure Effects are not applicable for an underfrequency relay.

7.6.8 Measuring and Test Equipment (MTE)

The following instrument is used to calibrate the underfrequency relays time delay, as shown in the block diagram (section 5.0) and Ref. 3.4.5:

 MTE_3 : Timer

The reference standards used for calibrating M&TE have an uncertainty (error) requirement of not more than 1/4 of the tolerance of the equipment being calibrated (Ref. 3.4.3).

Measuring and Test Equipment shall have an accuracy greater than or equal to that of the equipment being calibrated (Ref. 3.4.2).

Given the relative high accuracy of the M&TE, and the procedural guidelines stated above, it is conservative to assume that:

MTE **-** The value used as the relay Reference Accuracy (RA), including any M&TE reading error, and reference standard uncertainty.

Therefore,

 $MTE_3 = \pm 16$ % of setting

 \mathcal{L}

 $\bar{\gamma}$

 \sim

 $\overline{}$

 $\mathcal{L}^{\text{max}}_{\text{max}}$ and $\mathcal{L}^{\text{max}}_{\text{max}}$

 $\label{eq:2.1} \frac{1}{2} \int_{\mathbb{R}^3} \frac{1}{\sqrt{2}} \, \frac{1}{\sqrt{2}} \,$

 $\bar{\mathcal{L}}$

 $\hat{\mathcal{A}}$

FORM DCM 2, 4.2 (JAN. 1991)

 \sim \sim

 \bar{a}

 \sim

 $\ddot{}$

 $\bar{\lambda}$

 ϵ

 \sim

8.4 Underfrequency Relay

A 55 Hz Trip Setpoint was assumed in the Safety Analysis.

(page 14.1-42 of Ref. 3.2.3)

Therefore, AL *=* 55Hz

9.0 DETERMINE SETPOINT (TS)

CU is combined with the Analytical Limit in an appropriate direction, in order to determine the Trip Setpoint, as shown below.

9.1 Undervoltage (LOV) Setpoint

The positive value of CU is used for a decreasing variable, to insure that the relay will trip above the Analytical limit.

 $TS = AL + CU$ (Paragraph 7.0.6.2 of Ref. 3.1.4)

*⁼***78.2 +39** (+39 VAC, Sec. 7.0a)

118 VAC (rounded up to the nearest volt)

Given that the nominal potential transformer secondary voltage is only 6900 **VAC** x 120/7200 **- 115** VAC, this trip setpoint is not practical.

9.2 Undervoltage (LOV) Time Delay Relay Setpoint

The Undervoltage (LOV) Time Delay Analytical Limit (AL) is .6 Seconds (Sec. 8.2). The negative value of **CU** is used for an increasing variable to insure that channel trip occurs below the Analytical Limit.

 $TS = AL \pm CU$ (Ref. 3.1.4)

- .6 - **(.11)TS (-** 11% of setting, Sec. **7.0b)**

.6 $=$ $\frac{1}{(1+.11)}$

- **.54** Second (rounded down to the nearest hundredth)

9.3 Underfrequency Relay/Time Delay Setpoint

The Underfrequency Relay/Time Delay Analytical Limit (AL) is .7 sec. (Sec. 8.3). The negative value of **CU** is used for an increasing process variable (time). (para. 7.2 of ref. 3.1.3)

 $TS = AL + CU$ (Ref. 3.1.4)

= **.7** - (.25) **TS** (- **25%** of setting, Sec. 7.0c)

 $\ddot{}$

 $\frac{1}{2}$

J.

FORM **DCM** 2, 4.2 (JAN. 1991)

 $\mathcal{A}^{\mathcal{A}}$

Similarly,

 $e_{2 \text{CAL}} = \pm \sqrt{5^2 + 6.3^2 + 5^2}$ $=$ \pm 9.5% of Setting (Undervoltage Time Delay) e_{3CL} = $\pm \sqrt{0^2 + 19.4^2 + 16^2}$ **-** + **25%** of Setting (Underfrequency Time Delay) $e_{4CM} = \pm \sqrt{0^2 + 0^2 + 0^2 + 0^2}$ + **.53%** of Setting (Underfrequency)

10.2 AV for the Undervoltage **(LOV)** Setpoint

As shown in Sec. **9.1,** the calculated Trip Setpoint is not practical. Therefore, the Allowable Value can not be evaluated.

 $CU_{1CL} = N/A$ *AV, = N/A*

10.3 AV for the Undervoltage (LOV) Time Delay Setpoint

Given the definition of CU_{CAL} above, the Channel Uncertainty equation from Section 7.0 becomes:

 CU_{2CL} = $\pm \sqrt{e_{2CL}}$ $=$ \pm 9.5% of Setting AV_2 = TS \pm CU_{2CAL}

 $= .54 + (.095 X .54) = .59 \text{ sec}$, rounded down to nearest hundredth 10.4 AV for the Underfrequency Time Delay Setpoint

Similarly,

 $CU_{3CL} = \pm \sqrt{\theta_{3CL}^2}$ **-** + **25%** of Setting AV_3 = TS \pm CU_{3CAL}

 $= .5 + (.25 \times .5) = .6 \text{ sec}$, rounded down to nearest tenth 10.5 AV for the Underfrequency Trip Setpoint

Similarly,

 $CU_{\text{GAL}} = \pm \sqrt{e_{\text{GAL}}^2}$ **- ± .53%** of Setting $AV_4 = TS \pm CU_{4CAL}$ **- 57.5 - (.0053** x **57.5) - 57.2** Hz, rounded up to nearest tenth

 $\hat{\mathcal{A}}$

NOTES: **1.** The calculated Allowable Valve (AV) represents the limiting "As-Found" condition for the instrument loop.

- 2. 70% x 6900 VAC x 120/7200 80.5 VAC (page 2.3-3 of Ref. 3.2.4)
- 3. A Limiting Safety System Setting for Time Delay is not specified in the existing Technical Specification (page 2.3-3 of Ref. 3.2.4).
- 4. As shown in Section 9.1, the Westinghouse SV relay performance is not suitable for a 30 month calibration interval.

11.4 Undervoltage Relays:

This calculation demonstrates that the performance of the Westinghouse SV relay, based primarily on actual As-Found, As-Left plant data, is not suitable for a 24 month ± 25% calibration interval. The calibration interval for the SV relays should not be extended.

11.5 Undervoltage Time Delay and Underfrequency Relays:

The existing Setpoints provide sufficient margin to insure that channel trip will occur within the Analytical Limit (AL), for an extended twenty four (24) month ± 25% operating cycle. No setpoint changes are required.

12.0 ATTACHMENTS

1. Channel Uncertainty Equations (2 Shts.)

ATTACHMENT I **CHANNEL UNCERTAINTY EQUATIONS** SHEET 1 OF 2

1.0 Total Channel Uncertainty (CU)

The calculation of an instrument channel uncertainty can be performed with a single loop equation containing all potential uncertainty values, or by a series of related term equations. A specific channel calculation coincides with a channel's layout from process measurement to final output module or modules.

The typical linear channel uncertainty calculation has the following form:

 $CU^* = + \sqrt{PM^2 + PB^2 + IRE^2 + (Modul_{\theta_1})^2 + (Modul_{\theta_2})^2 + ... (Modul_{\theta_n})^2} + B^*$ $CU^* = -\sqrt{PM^2 + PE^2 + IRB^2 + (Module_1)^2 + (Module_2)^2 + \dots (Module_n)^2 - B^2}$

Where:

- Channel Uncertainty (CU) at a specific point in the channel: the CU =mCU can be calculated for any point in a channel from Module **1** to Module n, as needed.
- Random uncertainties that exist in the channel's basic Process PM Measurement (PM).
- PE = Random uncertainties that exist in a channel's Primary Element (PE), if it has one, such as the accuracy of a flowmeter table.
- IRE **-** Insulation resistance effect, leakage allowance in % of span.

MODULE **1,** 2, n - Total random uncertainty of each module that makes up the loop from Module **1** through Module n.

The total of all positive biases associated with a channel; this B^+ would include any uncertainties from PM, PE, or the Modules that could not be combined as a random term (biases, arbitrarily distributed uncertainties, and random bias).

- B^-
- The total of all negative biases associated with a channel.

ATTACHMENT I **CHANNEL UNCERTAINTY EQUATIONS** SHEET 2 OF 2

2.0 Module (en) Uncertainties

The individual module random uncertainties are in themselves a statistical combination of uncertainties. Depending on the type of module, its location, and the specific factors that can affect its accuracy, the determination of the module uncertainty will vary. For example, the module uncertainty for a module may be calculated as:

$$
e^* = \sqrt{RA^2 + DR^2 + TE^2 + RE^2 + SE^2 + HE^2 + SP^2 + PS^2 + MTE^2 + B^2}
$$

 $e^- = -\sqrt{RA^2 + DR^2 + TE^2 + RE^2 + SE^2 + HE^2 + SP^2 + PS^2 + MTE^2 - B^-}$

Where:

- e **-** Uncertainty of module,
- RA **-** Module Reference Accuracy specified by the manufacturer,
- $DR =$ Drift of the module over a specific period,
- TE Temperature Effect for the module; the effect of ambient temperature variations on module accuracy; the TE may be a normal operating TE, or an accident TE, as required,
- RE $=$ Radiation Effect for the module; the effect of radiation exposure on module accuracy; the RE may be a normal operating RE, an accident RE, or time of trip RE as required,
- SE = Seismic Effect or vibration effect for the module; the effect of seismic or operational vibration on the module accuracy,
- HE Humidity Effect for the module; the effect of changes in ambient humidity on module accuracy, if any,
- SP Static Pressure effects for the module; the effect of changes in process static pressure on module accuracy,
- MTE Measuring and Test Equipment effect for the module; this accounts for the uncertainties in the equipment utilized for calibration of the module, **m**

PS Power Supply effect,

 $B =$ Biases associated with the module, if any.

X **IP3 JAF**

INDEPENDENT DESIGN VERIFICATION CONTROL **SHEET**

^{*} Methods of verification: Design Review (DR), Alternate Calculations (AC), Qualification Test (QT)

DESIGN VERIFICATION CHECKLIST DESIGN REVIEW METHOD

 \bar{z}

 ~ 10

 \sim

 \bar{A}

 $\mathcal{L}_{\mathrm{in}}$

 $\mathcal{L}^{\text{max}}_{\text{max}}$

 $\hat{\mathcal{L}}$

 ω

DESIGN VERIFICATION CHECKLIST DESIGN REVIEW METHOD

10. Are the specified materials compatible with each other and the design environmental conditions to which the materials will be exposed? **11.** Have adequate maintenance features and requirements been satisfied? 12. Are accessibility and other design provisions adequate for performance of needed maintenance and repair? 13. Has adequate accessibility been provided to perform the in-service inspection expected to be required during the plant life? 14. Has the design properly considered radiation exposure to the public and plant personnel? (ALARA/cobalt reduction) 15. Are the acceptance criteria incorporated in the design documents sufficient to allow verification that design requirements have been satisfactorily accomplished? Yes/No/NA Yes/No

- 16. Have adequate pre-operational and subsequent periodic test requirements been appropriately specified?
- 17. Are adequate handling, storage, cleaning and shipping requirements specified?
- 18. Are adequate identification requirements specified?
- 19. Are the conclusions drawn in the Safety Evaluation fully supported by adequate discussion in the test or Safety Evaluation itself?
- 20. Are necessary procedural changes specified and are responsibilities for such changes clearly delineated?
- 21. Are requirements for record preparation, review, approval, retention, etc., adequately specified?
- 22. Have supplemental reviews by other engineering disciplines (seismic, electrical, etc.) been performed on the integrated design package?

Yes/No/Not Applicable

Form **DCM** 4, 4.2 (Page 2 of **3),** (MAR. 1989) **IP3-CALC-RPC-O0291**

DESIGN VERIFICATION CHECKLIST DESIGN REVIEW METHOD

Yes/No/Not Applicable

23. Have the drawings, sketches, calculations etc., included in the integrated design package been reviewed?

 (Yes) No/NA

24. References used as part of the design review which are not listed as part of the design calculation/analysis.

AO *AE* DESIGN VERIFIER: *_;", >2,? 'Z* <u>*DVMAZZZZZA*</u>
Signature/Date Supervising Engine \sqrt{n} Satery 4 **s-cco** *5 r* L/,, ce- s **C- .**